

# COHERENT EFFECTS IN THE IONIZATION LOSS OF HIGH-ENERGY ULTRASHORT ELECTRON BUNCHES



**S. V. Trofymenko**

*NSC “Kharkiv Institute of Physics and Technology”,*

*Karazin Kharkiv National University*

*Kharkiv, Ukraine*



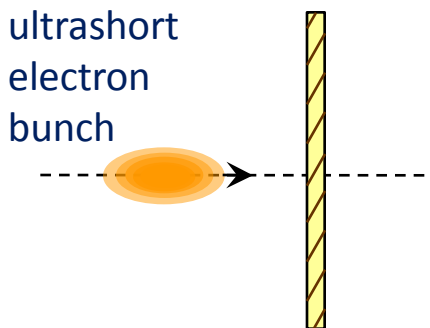
*Informal exchange meeting DESY/European XFEL – NSC KIPT  
July 15, 2022*

# COHERENT EFFECT IN IONIZATION LOSS OF ULTRASHORT ELECTRON BUNCHES

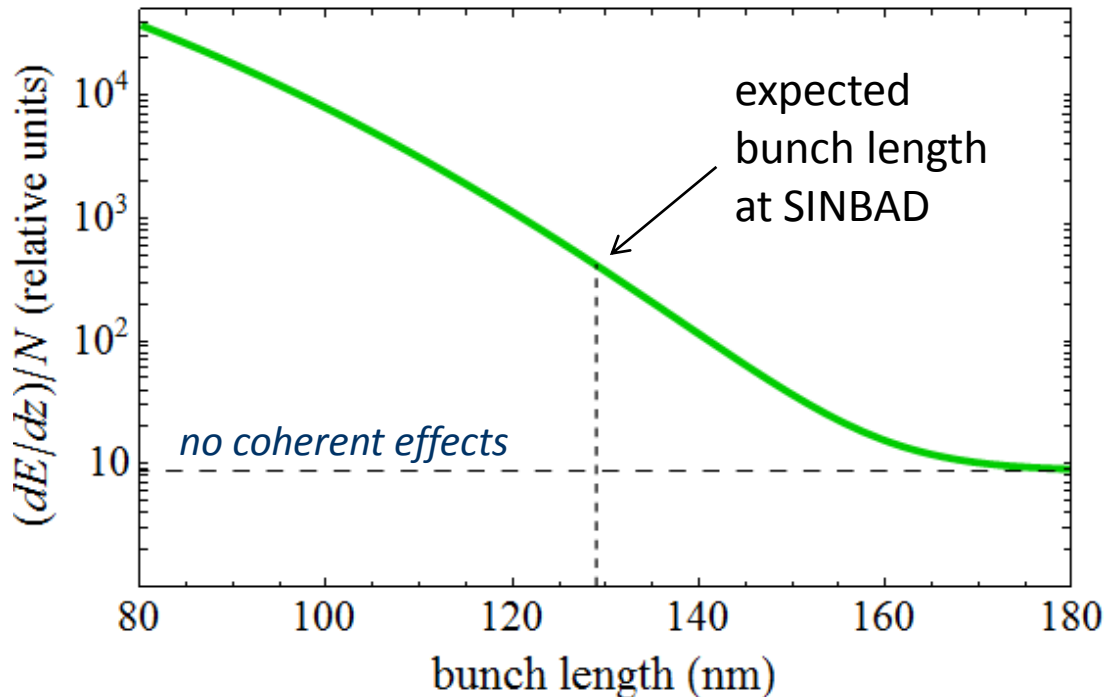
*S.V. Trofymenko, N.F. Shul'ga // Phys. Lett. A, 383 (2019) 2561*

Applicable for **European XFEL** and **SINBAD** at DESY

Possibility of enhancement of the ionization loss of ultrashort electron bunches by several orders of magnitude compared to the value from the Bethe-Bloch formula. Analogous enhancement is expected for characteristic radiation yield



Dependence of the ionization loss on the bunch length per single electron:



estimation for **SINBAD facility** at **DESY** (thin solid targets or gaseous targets)

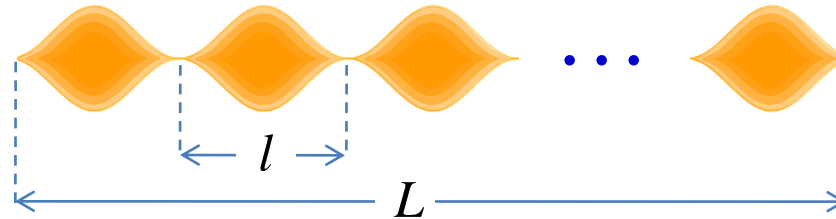
possibility of longitudinal and transversal bunch size diagnostics

# RESONANCE EFFECT IN THE IONIZATION LOSS OF A MICROBUNCHED BEAM

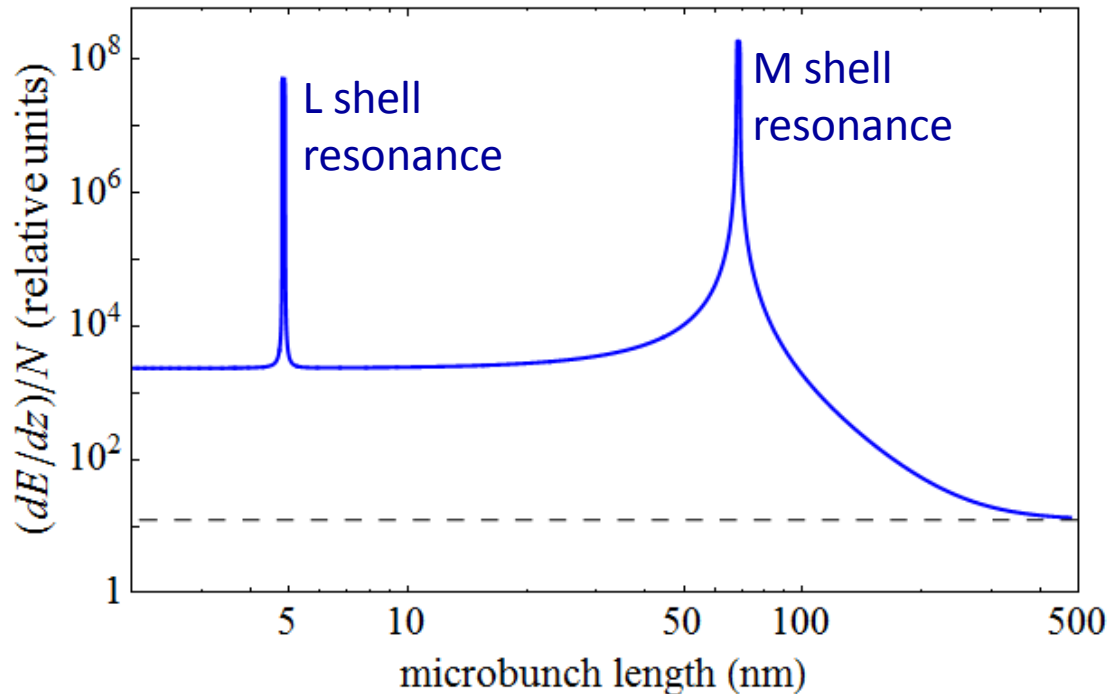
*S.V. Trofymenko, N.F. Shul'ga // Phys. Rev. Accel. Beams, 23 (2020) 084501*

$L$  – beam length

$l$  – microbunch length



Dependence of the ionization loss on the microbunch length in thin Si target:



Estimation for **European XFEL**  
( $L=24 \mu\text{m}$ ,  $Q \approx 1 \text{ nCl}$ ,  
 $E=17.5 \text{ GeV}$ )

possibility of studying the microbunching process and controlling the microbunching quality

# IONIZATION LOSS OF 'HALF-BARE' ELECTRONS IN THIN TARGET

*N.F. Shul'ga, S.V. Trofymenko // Phys. Lett. A, 376 (2012) 3572*

*S.V. Trofymenko, N.F. Shul'ga // Phys. Rev. Accel. Beams 19 (2016) 112801*

Previous studies on 'half-bare' electrons  
in NSC KIPT (for bremsstrahlung):

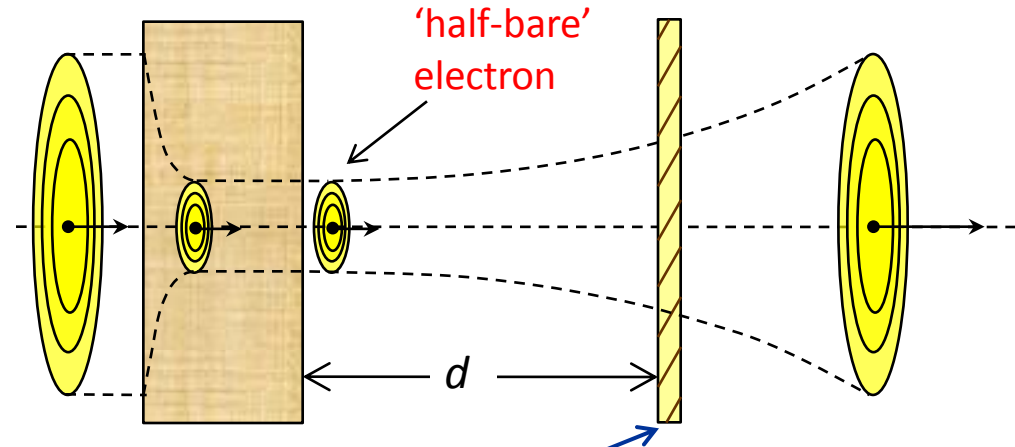
N.F. Shul'ga, S.P. Fomin, *JETP Lett.* (1978)

N.F. Shul'ga, S.P. Fomin, *Phys. Lett. A* (1986)

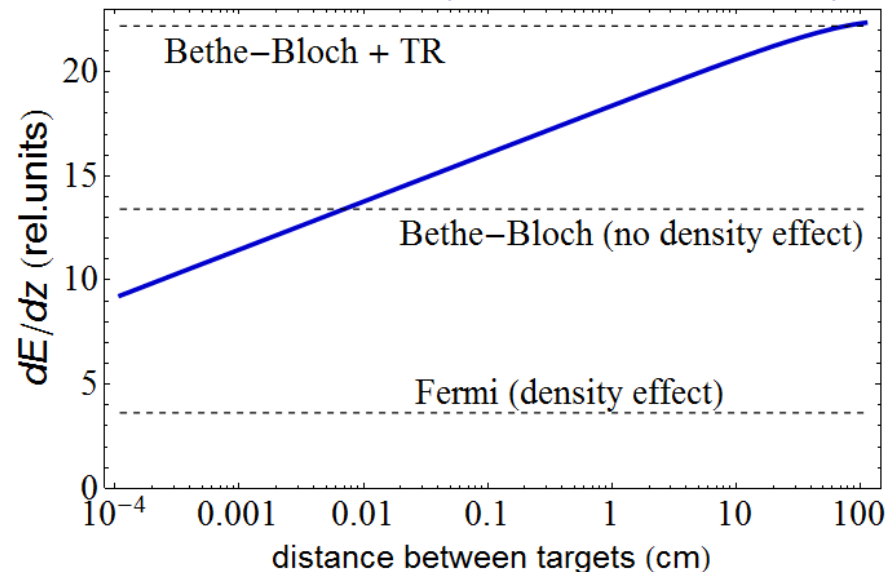
N.F. Shul'ga, S.P. Fomin, *JETP* (1998)

Experimental evidence (CERN NA63):

H.D. Thomsen et. al. *Phys. Lett. B* (2009)

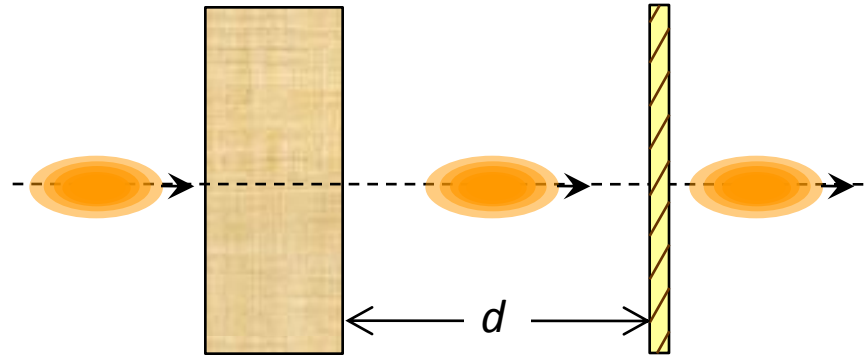


Electron ionization loss in thin target  
as a function of  $d$  (for 5 GeV electrons):

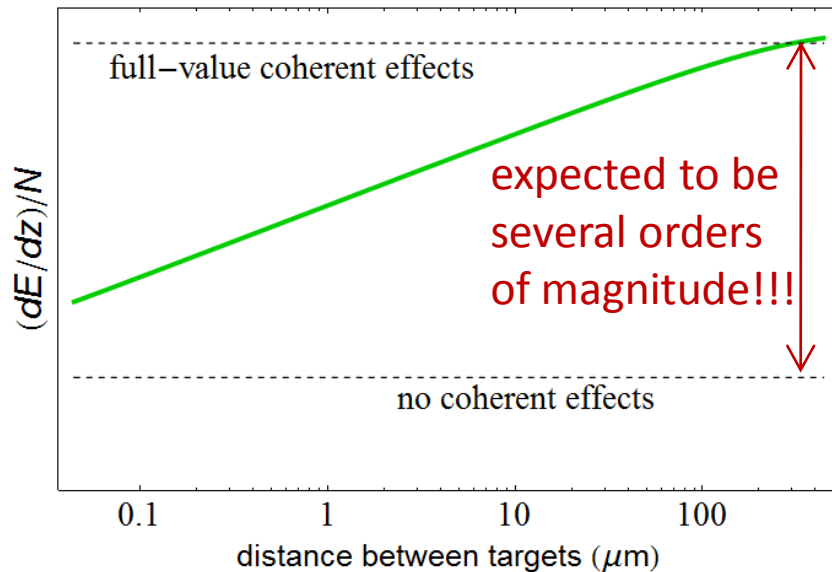


# IONIZATION LOSS OF 'HALF-BARE' ELECTRON BUNCHES IN THIN TARGET

Effects, associated with 'half-bare' electrons are expected to be considerably enhanced for ultrashort bunches due to coherent effects in the ionization loss



**ultrashort electron bunch (for 100 MeV, as at SINBAD):**

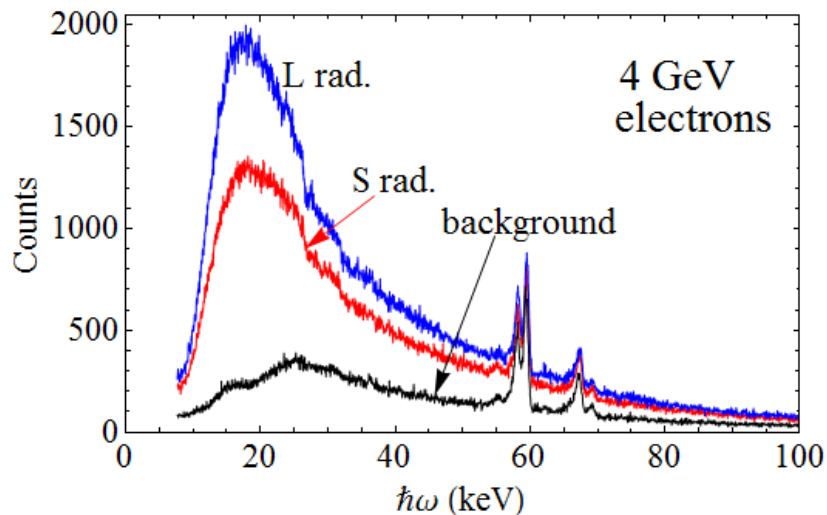
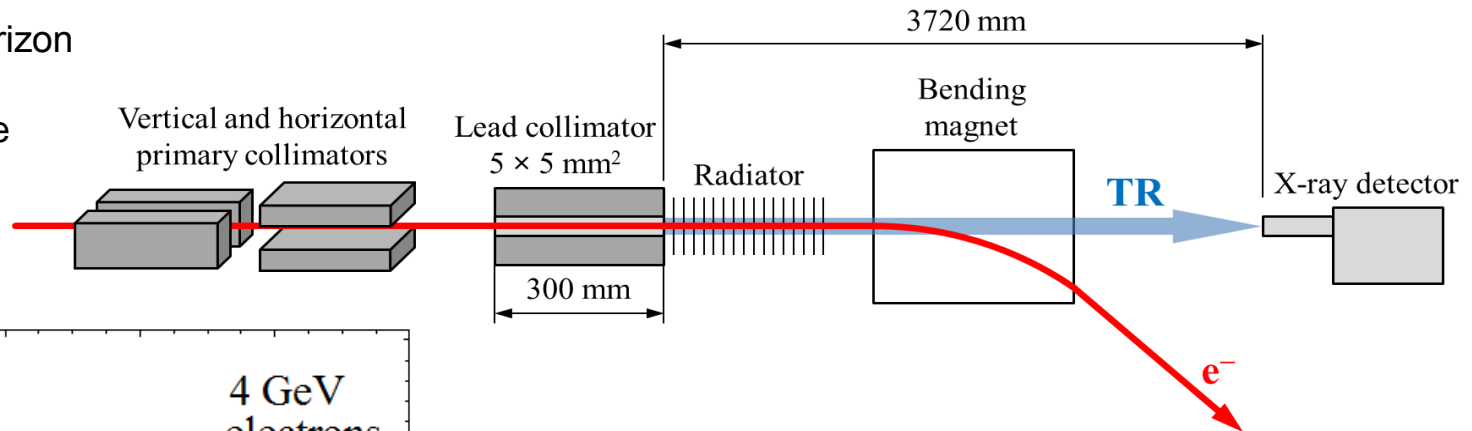


for small distance  $d$  – no coherent effects;  
for large  $d$  – full-value coherent effects  $\rightarrow$   
huge difference between the ionization loss values

# X-RAY TRANSITION RADIATION BY 'HALF-BARE' ELECTRONS. EXPERIMENT AT DESY II TEST BEAM (TB21)

*S.V. Trofymenko, R.M. Nazhmudinov, A.V. Shchagin, A.S. Kubankin, A.P. Potylitsyn, A.S. Gogolev, N.A. Filatov, G. Kube, N.A. Potylitsina-Kube, M. Stanitzki, R. Diener, A. Novokshonov, Nucl. Instrum. Meth. B, 476 (2020) 44*

European Union's Horizon  
2020 research and  
innovation programme  
(grant agreement No  
654168)



L radiator → period is 3 mm  
(‘dressed’ electrons)

S radiator → period is 0.3 mm  
(‘half-bare’ electrons)

Experiment on characteristic radiation (DESY II TB21):

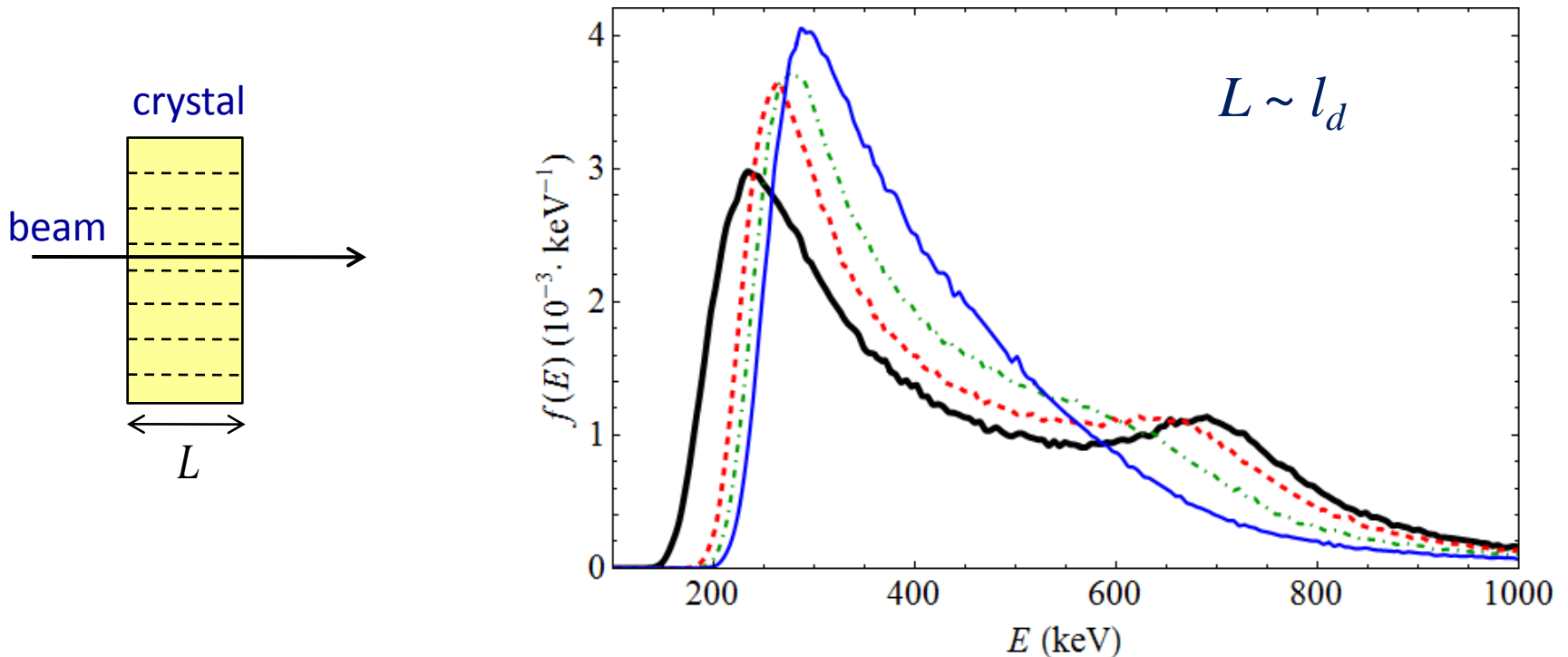
*R.M. Nazhmudinov, A.V. Shchagin, S.V. Trofymenko, I.A. Kishin, A.S. Kubankin, A.P. Potylitsyn, A.S. Gogolev, N.A. Filatov, G. Kube, N.A. Potylitsina-Kube, M. Stanitzki, A. Novokshonov, J. Phys. B: At. Mol. Opt. Phys., 54 (2021) 045201*

# IONIZATION LOSS SPECTRUM OF NEGATIVE CHanneled PARTICLES

*S.V. Trofymenko, I.V. Kyryllin, Eur. Phys. J. C, 80 (2020) 689*

*S.V. Trofymenko, I.V. Kyryllin, O.P. Shchus, East. Eur. J. Phys. 4, 68 (2021)*

Ionization loss distribution for different dechanneling lengths:



Possibility of the dechanneling length measurement on the basis of registration of the channeled particles ionization loss spectra

## CONCLUSIONS

- Possibility for the study of coherent effects in the ionization loss or characteristic radiation for electron bunch parameters achievable at SINBAD and European XFEL
- Possibility for the study of effects associated with ‘half-bare’ electrons due to their significant enhancement by the coherent effects
- Applicability for diagnostics of transversal and longitudinal bunch size and study of the microbunching process
- Dechanneling length measurement on the basis of registration of the channeled particles ionization loss spectra